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# Implementation of the Axness-Kerr Photocurrent Model

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# Introduction

- **QASPR – Qualification Alternatives to the Sandia Pulsed Reactor**
  - SPR decommissioned
  - Need for high-fidelity predictive models
  - My work concerned models for silicon BJTs. Comparing:
    - *Data from operational irradiation facilities (Medusa Linac and Little Mountain Linac)*
    - *Science-Based Modeling*
      - TCAD (Technology Computer Aided Design) Models
      - Compact Models
  - My Focus: Photocurrent models
    - *Also, effects of neutron damage on photocurrent generation*

# TCAD vs. Compact Models

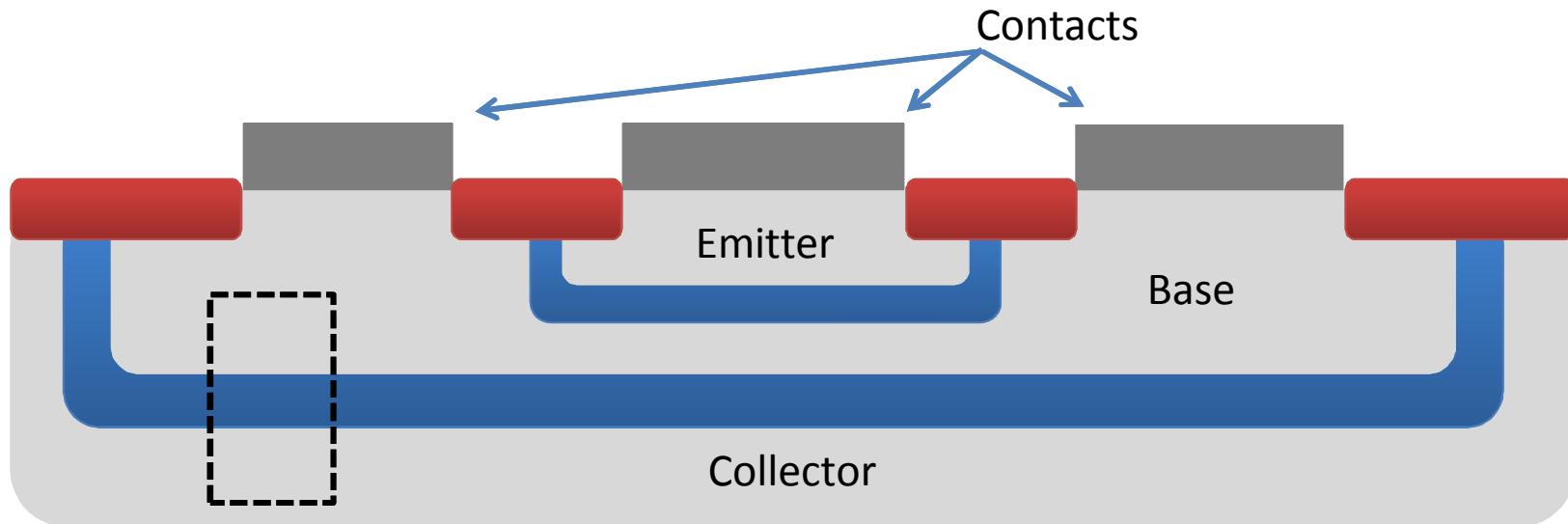
- **TCAD**

- *Medici*
- *Silvaco*
- *Charon*
- Highly accurate - Numerically solve carrier transport equations on finite mesh
- 1D, 2D, and 3D capabilities
- Device level calculations
- Computationally Expensive – Long runtimes for single devices

- **Compact models**

- Modular components of large scale circuit simulators
  - *Xyce* – *Designed for simulation of large systems using high performance computing (i.e. parallel computing)*
- Need to be much smaller and faster running
- Only support 1D modeling
- Require more calibration then TCAD models

# Photocurrent Background



BJT (Bipolar Junction Transistors):

- Silicon Substrate
- Doped with Boron and Phosphorous
- Considering NPN device (Emitter and Collector are N-type material, Base is P-type)
- From a photocurrent perspective, the junctions can be treated as (separate) diodes

# Photocurrent Background (Continued)



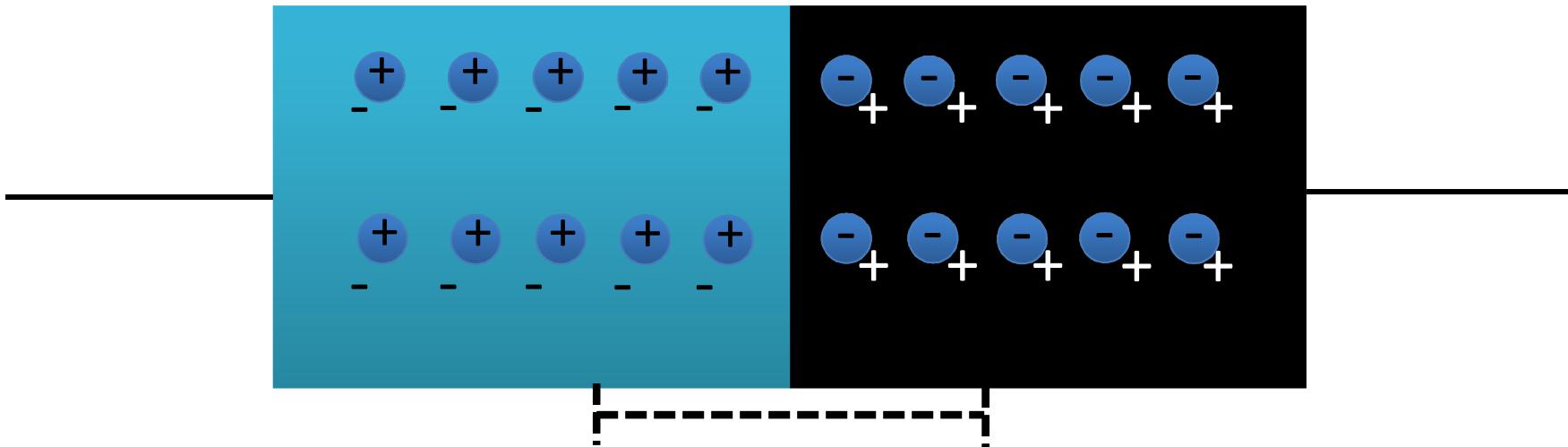
## Base

- Doped with Boron (Group III)
- Missing valence electrons
- Excess holes (positively charged majority carrier)
- P type material

## Collector

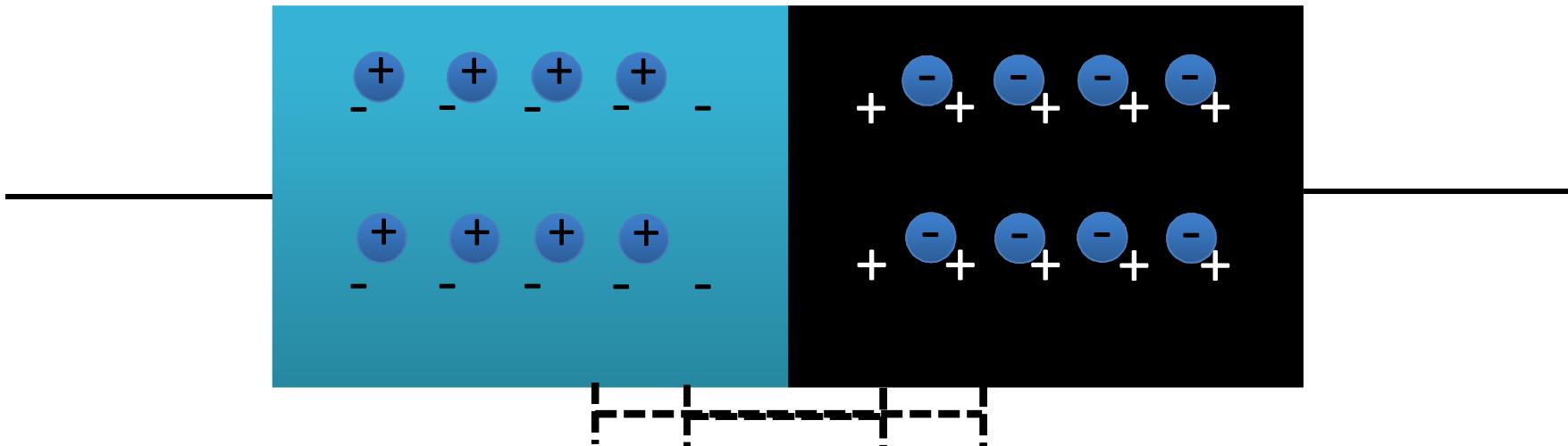
- Doped with Phosphorous (Group V)
- Has extra valence electrons
- Excess electrons (negatively charged majority carrier)
- N type material

# Photocurrent Background (Continued)



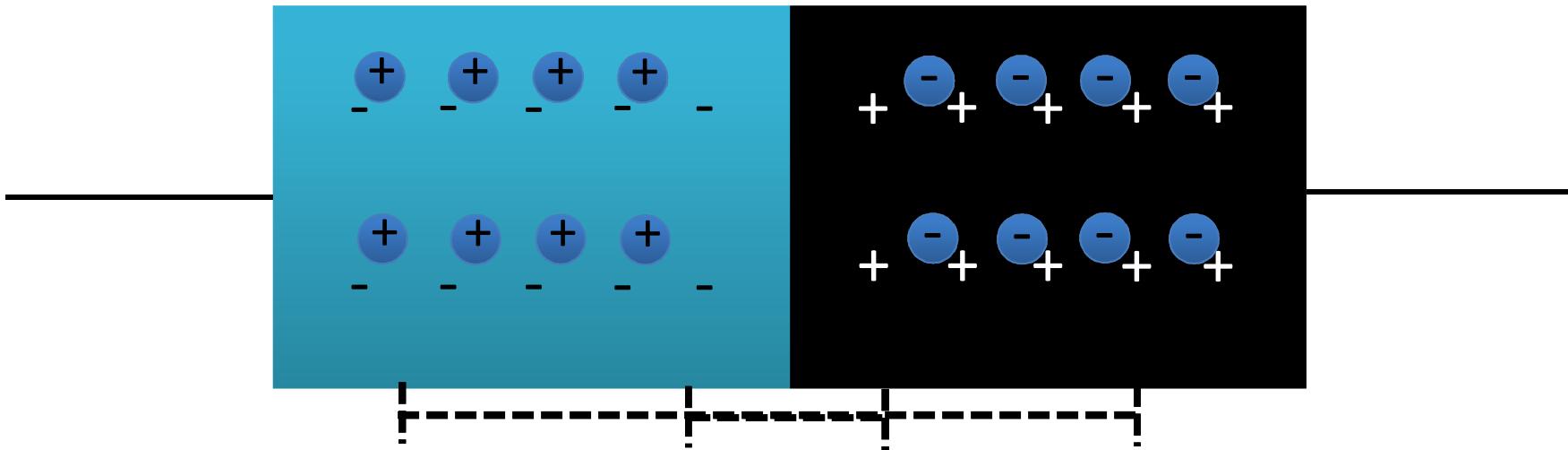
- Diffusion causes electrons to move from high concentration to low concentration. Creates electric field that prevents more charge from flowing (equilibrium state)

# Photocurrent Background (Continued)



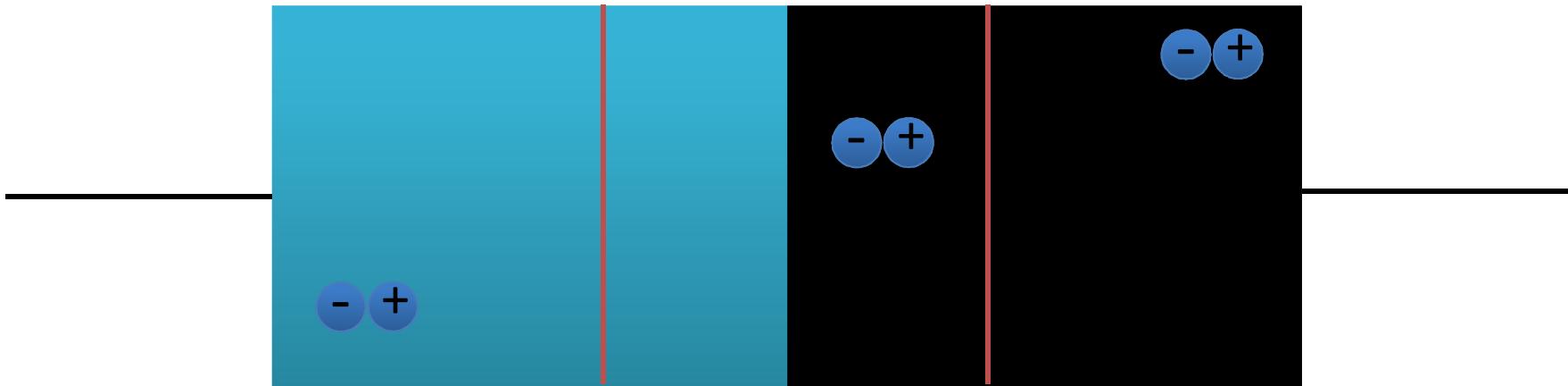
-Applying a forward bias shrinks the depletion region and allows more current to flow

# Photocurrent Background (Continued)



-Applying a reverse bias enlarges the depletion region, decreasing the output current

# Photocurrent Background (Continued)



- Photocurrent is induced when ionizing radiation strikes the device and creates an electron-hole pair.
- In the depletion region a high electric field separates the pair and accelerates them.
- In the quasi-neutral (undepleted) regions diffusion (and sometimes a small electric field) move the pairs.

# Compact Photocurrent Model

- Express photocurrent as current source from two diodes running in parallel to transistor.
- Photocurrent model is separate from regular operation model of BJT
- Does not fully solve transport equations:
  - Utilizes 1D Ambipolar Diffusion equation to approximate current contributions from quasi-neutral regions of device

$$\frac{\partial u}{\partial t} = D_a \frac{\partial^2 u}{\partial x^2} - \mu_a E \frac{\partial u}{\partial x} - \frac{1}{\tau} u + g(t)$$

$u$  = excess carrier density

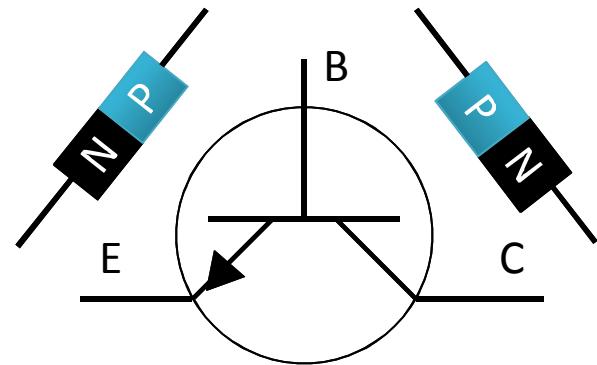
$D$  = ambipolar diffusion coefficient

$E$  = Electric field

$\mu$  = ambipolar mobility

$\tau$  = carrier lifetime

$g$  = e-h pair generation rate

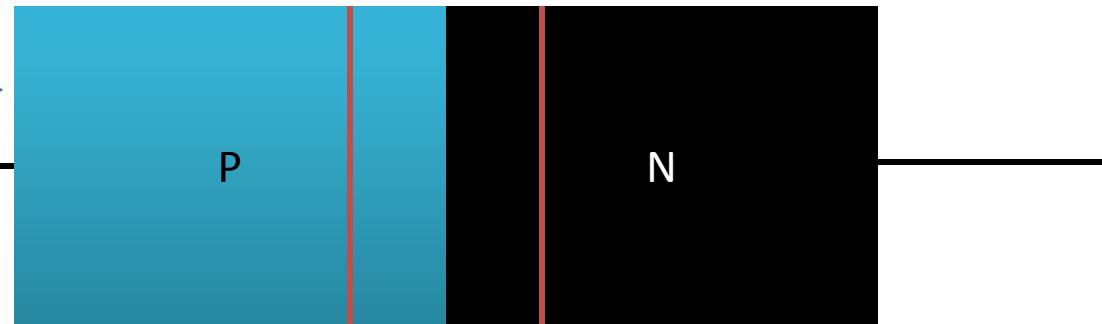


# The Tor Fjeldly Model

Depletion region:  
Current is field driven

- Assume abrupt P-N junction

Undepleted P-type region:  
Current is diffusion driven



Undepleted N-type region:  
Current is diffusion driven

- Assume majority of voltage drop is across depletion region

- Field strength high enough to move carriers to terminals immediately after generation
    - Assume recombination is negligible in depletion region
    - No delay in prompt photocurrent

- Diffusion current is determined by the ADE

- Decay tails (residual current after pulse ends)

- Approximated by a calibrated RC circuit model

# Limitations of the Tor Fjeldly Model

- **Does not actually solve the Ambipolar Diffusion Equation**
  - Only derives steady state solution
  - Time dependent effects utilize RC circuit approximation
- **RC circuit model of current decay tails difficult to calibrate**
  - Carrier diffusivities and lifetimes had to be calibrated well outside physical boundaries in order to match experimental data
- **No mechanism to accommodate damage to device during  $\gamma$ -irradiation**
  - Need reliable way to model photocurrent response during neutron pulse

# The Axness-Kerr Photocurrent Model

- Also solves ADE for an abrupt P-N junction
- Uses Fourier series to derive partial closed form solution to ADE
  - Solutions for various irradiation profiles
    - *Step functions*
    - *Square pulses*
    - *Piecewise linear generation rates*
- Mathematics developed to include description of effects on photocurrent response due to abrupt changes in carrier lifetimes
  - Neutron pulses can create interstitial defects in semiconductor lattice- leads to electron hole recombination sites and changes in carrier lifetimes
- Includes description of delay in photocurrent generated in depletion region
- Will include updated model of current generation from the subcollector
- Currently working on:
  - Approximation to moving boundary problem for a piecewise linear/piecewise constant device bias.
  - Convergence analysis to communicate with solvers in XYCE

# Implementation

- Started with standalone version written in standard C
  - Goal is to calibrate parameters in model using CHARON
  - Then we can run comparisons between the A-K model, the Tor Fjeldly model, TCAD models, and experimental data
- Working on version in C++ to ultimately integrate into XYCE
  - The photocurrent ‘sources’ run in parallel to the normal function of the transistor, so they can be implemented alongside other models.
  - Currently considers the BJT as two connected diodes
  - Template functions designed to utilize the SACADO automatic differentiation library
    - *Used to find voltage-derivatives for use in XYCE’s solvers*

# Newton's method iterates and SACADO

- SACADO is a C++ library developed at Sandia as part of the Trilinos Package
  - Uses template features in C++ to build derivative functions at compile time.
  - We are using forward mode AD, essentially a chain rule process
- Derivatives do not need to be recomputed if code/model is changed, functions need only be properly templated
- Derivatives of current with respect to voltage are used by XYCE to calculate voltages at each node in the system
  - Solving n-by-n system generated using Kirchhoff's current rule (  $\sum_k I_k = 0$  )
  - Uses Newton's method to find zeros of:  $F : \vec{V} \rightarrow \vec{I}$
  - $J_F(V_m)\Delta V = -F(V_m)$  where  $J_F$  is the Jacobian of  $F$ ,  $J_{ij} = \left[ \frac{\partial F_i}{\partial V_j} \right]$
  - $V_{m+1} = V_m + \Delta V$

# Current and Future Work

- Account for changing device bias.
  - Piecewise linear
  - Piecewise constant
- On-the-fly error analysis
  - Communicating a measure of convergence to XYCE
- Modify standalone code to fit into XYCE
- Calibrate parameters using TCAD models
- Run comparisons between different compact models, TCAD models, and data.

# Acknowledgements

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# Questions